

4P04L04-VB TO263 Datasheet P-Channel 40-V (D-S) MOSFET

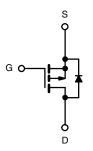
PRODUCT SUMMARY						
V _{DS} (V)	$r_{DS(on)}(\Omega)$	I _D (A) ^a	Q _g (Typ.)			
- 40	0.0041 at V _{GS} = - 10 V	- 110	185 nC			

FEATURES

• TrenchFET® Power MOSFET







P-Channel MOSFET

Parameter	Symbol	Limit	Unit		
Drain-Source Voltage	V _{DS}	- 40	V		
Gate-Source Voltage	V _{GS}	± 20	v		
	T _C = 25 °C		- 110 ^a		
Continuous Drain Current /T 175 °C\	T _C = 70 °C		- 110 ^a		
Continuous Drain Current (T _J = 175 °C)	T _A = 25 °C	I _D	39 ^{b, c}		
	T _A = 70 °C		33 ^{b, c}	A	
Pulsed Drain Current	•	I _{DM}	240		
Continuous Course Dunin Biode Course	T _C = 25 °C		110		
Continuous Source-Drain Diode Current	T _A = 25 °C	I _S	10 ^{b, c}		
Avalanche Current	. 04	I _{AS}	75		
Single-Pulse Avalanche Energy L = 0.1 mH		E _{AS}	281	mJ	
	T _C = 25 °C		375		
Maximum Davier Dissipation	T _C = 70 °C	В	262	14/	
Maximum Power Dissipation	T _A = 25 °C	P _D	15 ^{b, c}	W	
	T _A = 70 °C		10.5 ^{b, c}		
Operating Junction and Storage Temperature Range		T _J , T _{stg}	- 55 to 175		
Soldering Recommendations (Peak Temperature		260	°C		

THERMAL RESISTANCE RATINGS						
Parameter		Symbol	Typical	Maximum	Unit	
Maximum Junction-to-Ambient ^{b, d}	t ≤ 10 s	R_{thJA}	8	10	°C/W	
Maximum Junction-to-Case (Drain)	Steady State	R_{thJC}	0.33	0.4	1 *C/W	

Notes:

- a. Package limited.b. Surface Mounted on 1" x 1" FR4 board.
- d. Maximum under Steady State conditions is 40 °C/W.



Parameter	Symbol	Test Conditions	Min.	Тур.	Max.	Unit
Static						
Drain-Source Breakdown Voltage	V _{DS}	$V_{GS} = 0 \text{ V}, I_D = -250 \mu\text{A}$	- 40			V
V _{DS} Temperature Coefficient	$\Delta V_{DS}/T_{J}$	I _D = - 250 μA		- 40		mV/°C
V _{GS(th)} Temperature Coefficient	$\Delta V_{GS(th)}/T_J$	η = - 250 μΑ		- 5.5		
Gate-Source Threshold Voltage	V _{GS(th)}	$V_{DS} = V_{GS}, I_{D} = -250 \mu A$	- 2	- 3	- 4	V
Gate-Source Leakage	I _{GSS}	$V_{DS} = 0 \text{ V}, V_{GS} = \pm 20 \text{ V}$			± 100	nA
Zovo Coto Voltogo Dvoin Cuvvent	1	V _{DS} = - 40 V, V _{GS} = 0 V			- 1	μΑ
Zero Gate Voltage Drain Current	IDSS	$V_{DS} = -40 \text{ V}, V_{GS} = 0 \text{ V}, T_{J} = 55 ^{\circ}\text{C}$			- 10	
On-State Drain Current ^a	I _{D(on)}	$V_{DS} \ge 5 \text{ V}, V_{GS} = -10 \text{ V}$	- 120			Α
Drain-Source On-State Resistance ^a	r _{DS(on)}	V _{GS} = - 10 V, I _D = - 20 A		0.0041		Ω
Forward Transconductance ^a	g_{fs} $V_{DS} = -15 \text{ V}, I_D = -20 \text{ A}$			75		S
Dynamic ^b						
Input Capacitance	C _{iss}			11300		pF
Output Capacitance	C _{oss}	V _{DS} = - 25 V, V _{GS} = 0 V, f = 1 MHz		1510		
Reverse Transfer Capacitance	C _{rss}			1000		
Total Gate Charge	Q_g			185	280	nC
Gate-Source Charge	Q _{gs}	V _{DS} = - 20 V, V _{GS} = - 10 V, I _D = - 110 A		48		
Gate-Drain Charge	Q_{gd}			42		
Gate Resistance	R_{g}	f = 1 MHz		4.0		Ω
Turn-On Delay Time	t _{d(on)}			25	40	ns
Rise Time	t _r	$V_{DD} = -20 \text{ V}, R_{L} = 0.18 \Omega$		290	440	
Turn-Off Delay Time	t _{d(off)}	$I_D \cong$ - 110 A, V_{GEN} = - 10 V, R_g = 1 Ω		110	165	
Fall Time	t _f			35	55	
Drain-Source Body Diode Characteristic	s	,			I.	
Continuous Source-Drain Diode Current	I _S	T _C = 25 °C			- 110	_
Pulse Diode Forward Current ^a	I _{SM}				- 240	Α
Body Diode Voltage	V_{SD}	I _S = - 20 A		- 0.8	- 1.5	V
Body Diode Reverse Recovery Time	t _{rr}			70	105	ns
Body Diode Reverse Recovery Charge	Q _{rr}	1 - 20 A di/dt - 100 A/up T 25 °C		130	200	nC
Reverse Recovery Fall Time	t _a	$I_F = -20 \text{ A}, \text{ di/dt} = 100 \text{ A/}\mu\text{s}, T_J = 25 ^{\circ}\text{C}$		37		
Reverse Recovery Rise Time	t _b	-		33		ns

Notes:

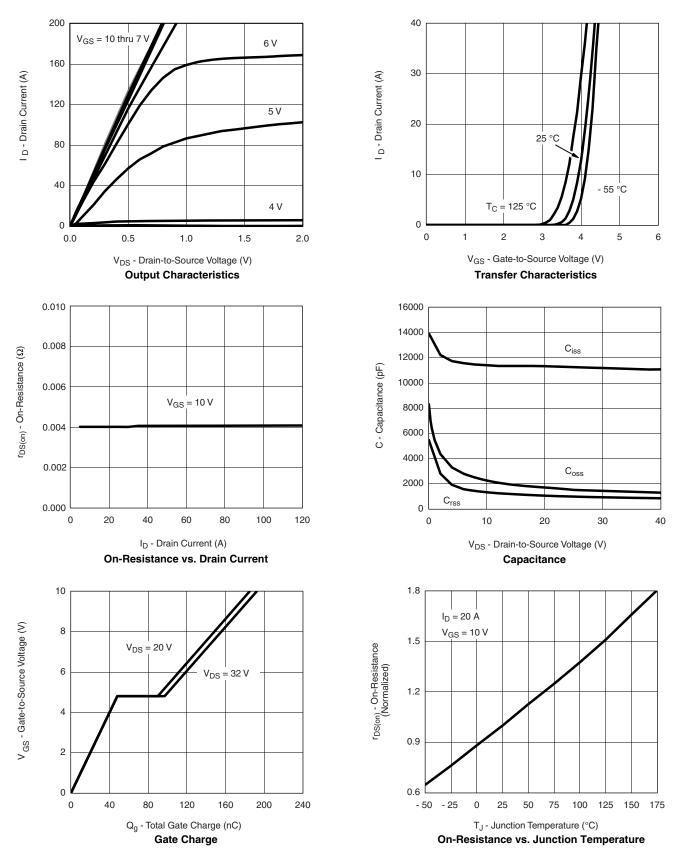
Stresses beyond those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated in the operational sections of the specifications is not implied. Exposure to absolute maximum rating conditions for extended periods may affect device reliability.

a. Pulse test; pulse width $\leq 300~\mu s,$ duty cycle $\leq 2~\%.$

b. Guaranteed by design, not subject to production testing.

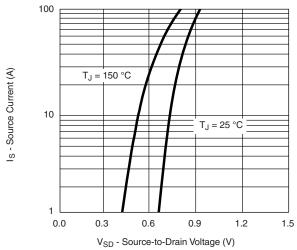


TYPICAL CHARACTERISTICS 25 °C, unless otherwise noted

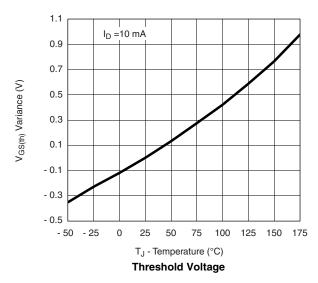




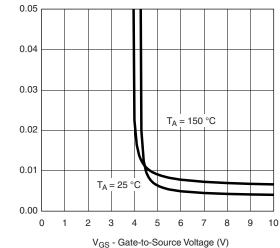
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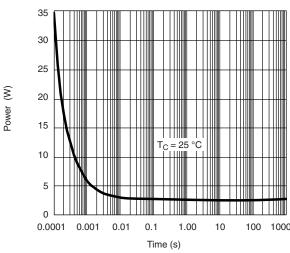
Source-Drain Diode Forward Voltage



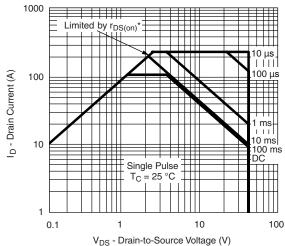
 $r_{DS(on)}$ - Drain-to-Source On-Resistance (Ω)



On-Resistance vs. Gate-to-Source Voltage



Single Pulse Power, Junction-to-Ambient

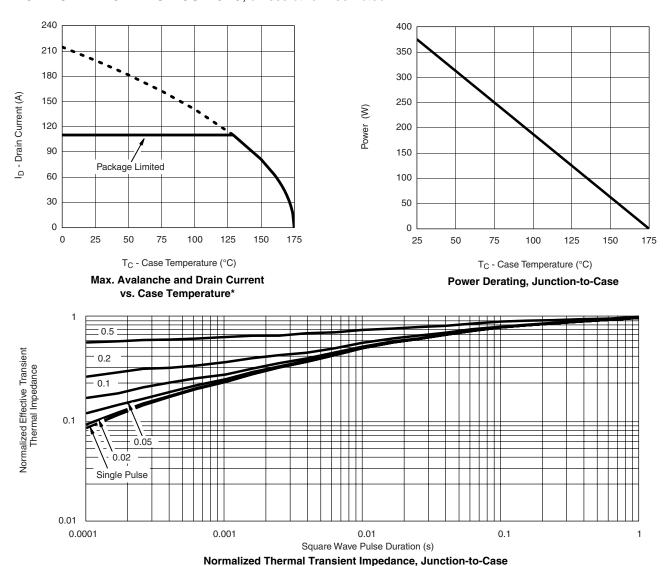


 $^*\mbox{V}_{\mbox{GS}} > \mbox{minimum} \mbox{ V}_{\mbox{GS}}$ at which $\mbox{r}_{\mbox{DS}(\mbox{on})}$ is specified

Safe Operating Area, Junction-to-Case



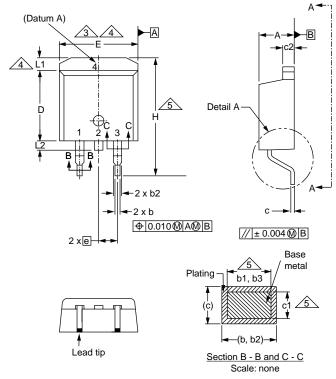
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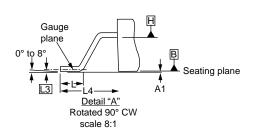


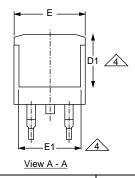
^{*} The power dissipation P_D is based on $T_{J(max)} = 175$ °C, using junction-to-case thermal resistance, and is more useful in settling the upper dissipation limit for cases where additional heatsinking is used. It is used to determine the current rating, when this rating falls below the package limit.



TO-263AB







	MILLIN	METERS	INCHES		
DIM.	MIN.	MAX.	MIN.	MAX.	
Α	4.06	4.83	0.160	0.190	
A1	0.00	0.25	0.000	0.010	
b	0.51	0.99	0.020	0.039	
b1	0.51	0.89	0.020	0.035	
b2	1.14	1.78	0.045	0.070	
b3	1.14	1.73	0.045	0.068	
С	0.38	0.74	0.015	0.029	
c1	0.38	0.58	0.015	0.023	
c2	1.14	1.65	0.045	0.065	
D	8.38	9.65	0.330	0.380	

	MILLIMETERS		INC	HES
DIM.	MIN.	MAX.	MIN.	MAX.
D1	6.86	-	0.270	-
Е	9.65	10.67	0.380	0.420
E1	6.22	-	0.245	-
е	2.54 BSC		0.100 BSC	
Н	14.61	15.88	0.575	0.625
L	1.78	2.79	0.070	0.110
L1	-	1.65	-	0.066
L2	-	1.78	-	0.070
L3	0.25 BSC		0.010	BSC
L4	4.78	5.28	0.188	0.208

ECN: S-82110-Rev. A, 15-Sep-08

DWG: 5970

Notes

- 1. Dimensioning and tolerancing per ASME Y14.5M-1994.
- 2. Dimensions are shown in millimeters (inches).
- 3. Dimension D and E do not include mold flash. Mold flash shall not exceed 0.127 mm (0.005") per side. These dimensions are measured at the outmost extremes of the plastic body at datum A.
- 4. Thermal PAD contour optional within dimension E, L1, D1 and E1.
- 5. Dimension b1 and c1 apply to base metal only.
- 6. Datum A and B to be determined at datum plane H.
- 7. Outline conforms to JEDEC outline to TO-263AB.



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